Docket #: P/2699-26
Title: FILM THICKNESS MEASURING METHOD, RELATIVE
DIELECTRIC CONSTANT MEASURING METHOD, FILM THICKNESS
MEASURING APPARATUS, AND RELATIVE DIELECTRIC CONSTANT
MEASURING APPARATUS
Inventors: T. Kitajima et al.
Drawings 4 sheets (Figs. 1-5)
Contact: J. Finder (212) 382-0700

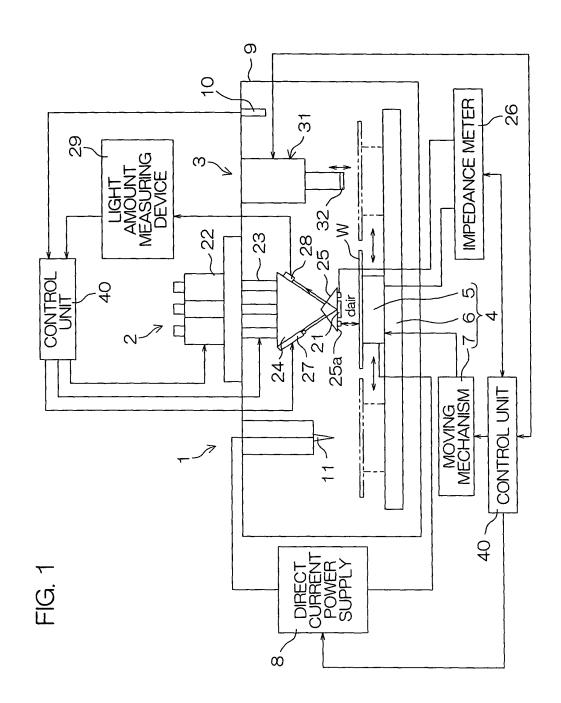
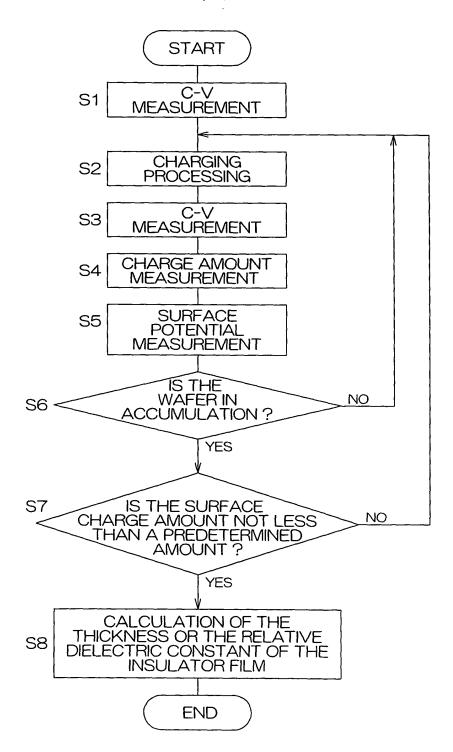
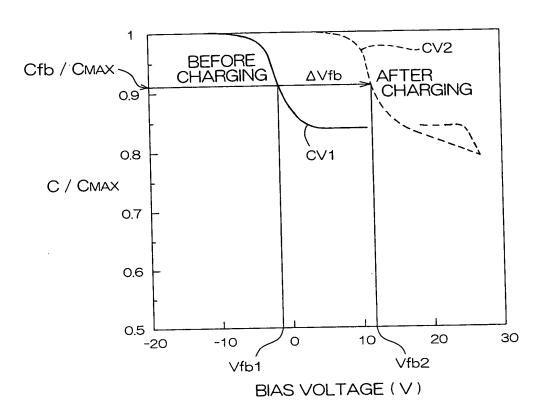


FIG. 2



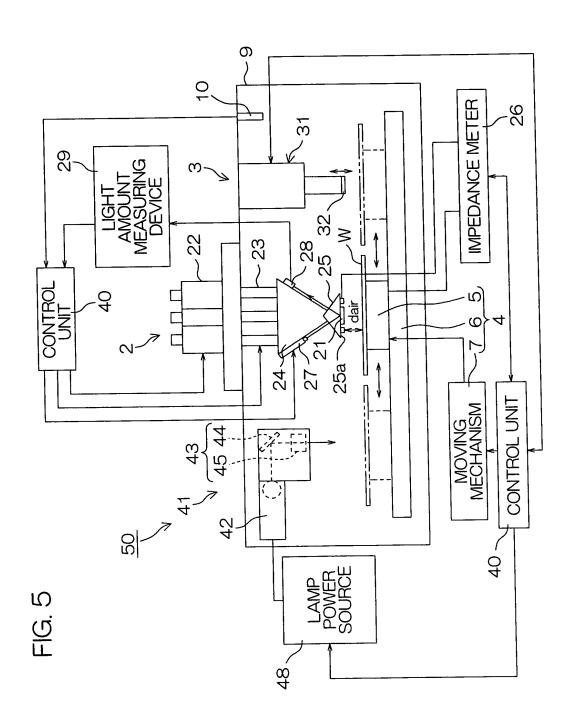
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FIG. 3

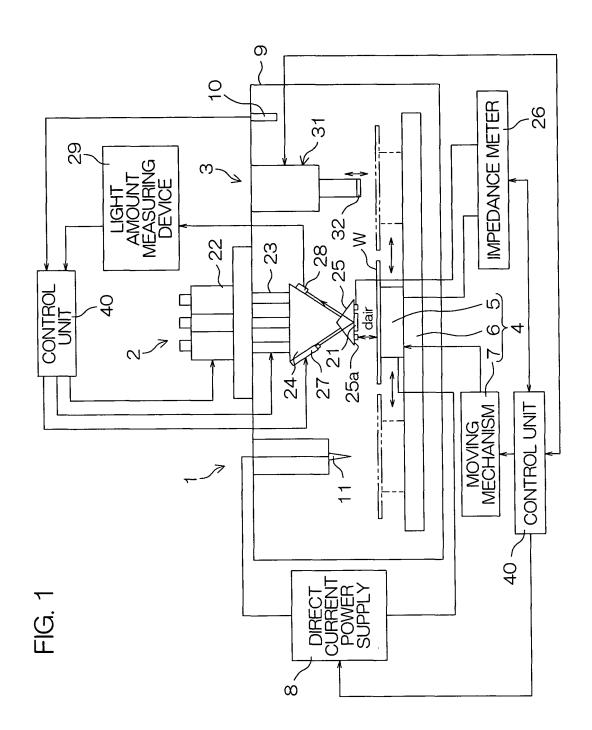


CHARGE AMOUNT Q SURFACE POTENTIAL Vsurf

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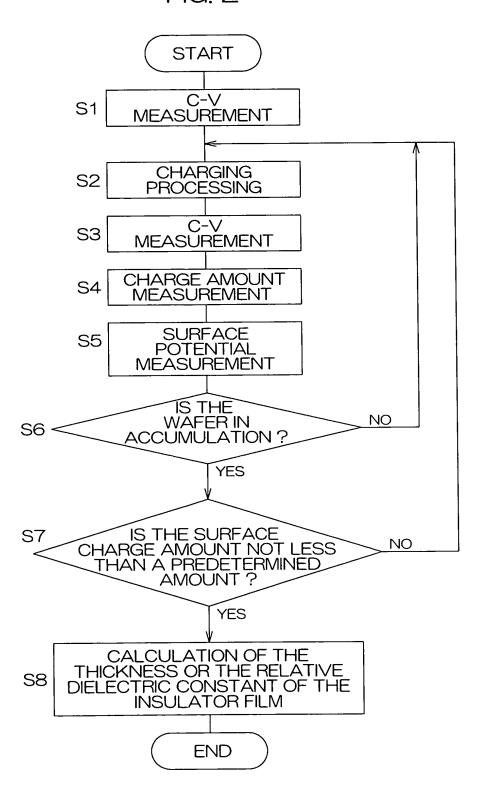


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\*\*Total Constant Const

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FIG. 2



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FIG. 3

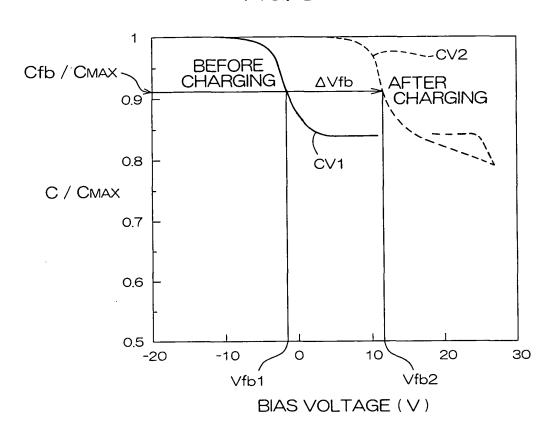


FIG. 4 CHARGE AMOUNT SURFACE POTENTIAL Vsurf

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